

OptiMOS™-T2 Power-Transistor





Features

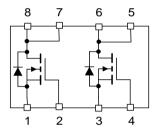
- Dual N-channel Logic Level Enhancement mode
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested

Product Summary

V _{DS}	60	V
R _{DS(on),max} ⁴⁾	26	mΩ
I _D	20	Α

PG-TDSON-8





Туре	Package	Marking
IPG20N06S4L-26	PG-TDSON-8	4N06L26

Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current one channel active	I _D	T _C =25 °C, V _{GS} =10 V ¹⁾	20	Α
		T _C =100 °C, V _{GS} =10 V ²⁾	18	
Pulsed drain current ²⁾ one channel active	I _{D,pulse}	-	80	
Avalanche energy, single pulse ^{2, 4)}	E _{AS}	/ _D =10A	35	mJ
Avalanche current, single pulse ⁴⁾	IAS	-	15	А
Gate source voltage	V_{GS}	-	±16	V
Power dissipation one channel active	P_{tot}	T _C =25 °C	33	w
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 + 175	°C



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	4.5	K/W
SMD version, device on PCB	R_{thJA}	minimal footprint	-	100	-	
		6 cm ² cooling area ³⁾	-	60	-	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	$V_{\rm GS}$ =0 V, $I_{\rm D}$ = 1 mA	60	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=10\mu{\rm A}$	1.2	1.7	2.2]
Zero gate voltage drain current ⁴⁾	I _{DSS}	$V_{\rm DS} = 60 \text{ V}, V_{\rm GS} = 0 \text{ V}, $ $T_{\rm j} = 25 \text{ °C}$	1	0.01	1	μA
		$V_{\rm DS}$ =60 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C ²⁾	-	5	100	
Gate-source leakage current ⁴⁾	I _{GSS}	V _{GS} =16 V, V _{DS} =0 V	-	-	100	nA
Drain-source on-state resistance ⁴⁾	R _{DS(on)}	V _{GS} =4.5 V, I _D =10 A	1	31	46	mΩ
		V _{GS} =10 V, I _D =17 A	-	21	26	



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance ⁴⁾	C _{iss}		-	1100	1430	pF
Output capacitance ⁴⁾	Coss	V _{GS} =0 V, V _{DS} =25 V, f=1 MHz	-	300	390	
Reverse transfer capacitance ⁴⁾	C _{rss}		-	18	36	
Turn-on delay time	$t_{\sf d(on)}$		-	5	-	ns
Rise time	t _r	V _{DD} =30 V, V _{GS} =10 V,	-	1.5	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =20 A, $R_{\rm G}$ =11 Ω	-	18	-	
Fall time	t_{f}		-	10	-	
Gate Charge Characteristics ^{2, 4)}						
Gate to source charge	Q _{gs}		-	4.3	5.6	nC
Gate to drain charge	Q _{gd}	V_{DD} =48 V, I_{D} =20 A, V_{GS} =0 to 10 V	-	1.7	3.4	1
Gate charge total	Qg		-	15	20	1
Gate plateau voltage	V _{plateau}		-	3.9	-	V
Reverse Diode	•					
Diode continous forward current ²⁾ one channel active	Is	- T _C =25 °C	-	-	20	А
Diode pulse current ²⁾ one channel active	I _{S,pulse}	7 _C =23 C	-	-	80	
Diode forward voltage	V_{SD}	V _{GS} =0 V, I _F =17 A, T _j =25 °C	-	0.95	1.3	V
Reverse recovery time ²⁾	t _{rr}	V_{R} =30 V, I_{F} = I_{S} , di_{F} / dt =100 A/ μ s	-	33	-	ns
Reverse recovery charge ^{2, 4)}	Q _{rr}		-	30	-	nC

 $^{^{1)}}$ Current is limited by bondwire; with an $R_{\rm thJC}$ = 4.5K/W the chip is able to carry 26.6A at 25°C.

²⁾ Specified by design. Not subject to production test.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

⁴⁾ Per channel



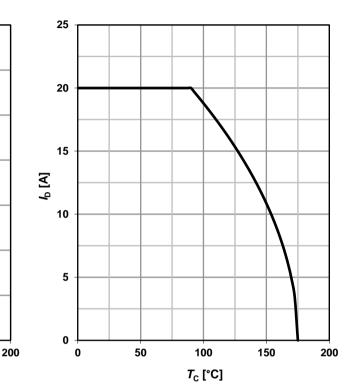
1 Power dissipation

 $P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}; \text{ one channel active}$

35 30 25 20 20 20 20 15

2 Drain current

 $I_D = f(T_C)$; $V_{GS} \ge 6 \text{ V}$; one channel active



3 Safe operating area

5

0

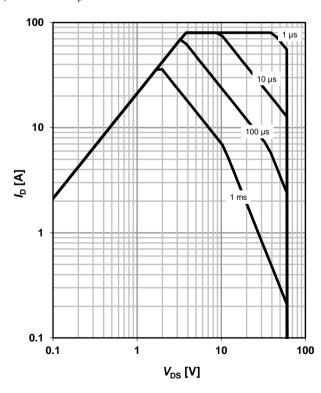
 $I_{\rm D}$ =f($V_{\rm DS}$); $T_{\rm C}$ =25°C; D=0; one channel active parameter: $t_{\rm p}$

100

*T*_C [°C]

150

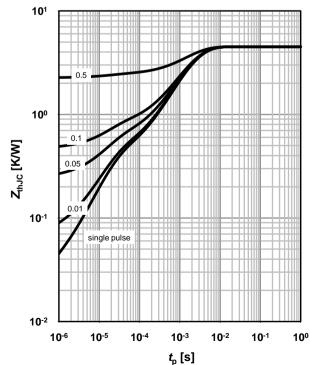
50



4 Max. transient thermal impedance

 $Z_{\text{thJC}} = f(t_p)$

parameter: $D=t_p/T$





5 Typ. output characteristics⁴⁾

 $I_D = f(V_{DS}); T_i = 25 \text{ °C}$

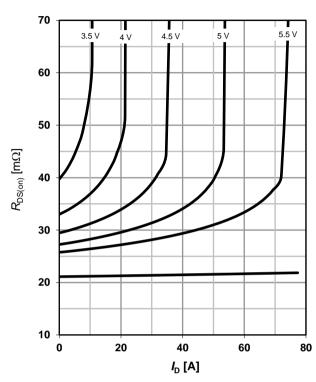
parameter: V_{GS}

80 60 5 V 20 0 1 2 3 4 5 V_{DS} [V]

6 Typ. drain-source on-state resistance⁴⁾

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}$

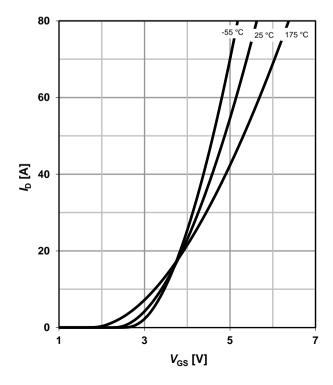
parameter: V_{GS}



7 Typ. transfer characteristics⁴⁾

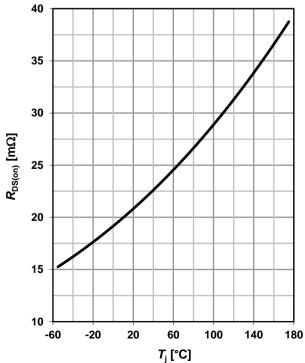
 $I_D = f(V_{GS}); V_{DS} = 6V$

parameter: $T_{\rm j}$



8 Typ. drain-source on-state resistance⁴⁾

$$R_{DS(on)} = f(T_j); I_D = 17 \text{ A}; V_{GS} = 10 \text{ V}$$





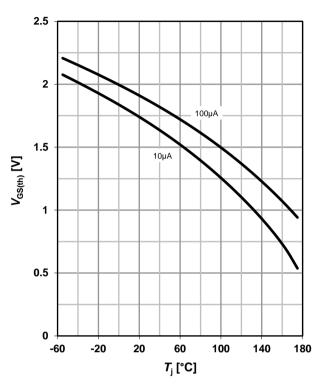
9 Typ. gate threshold voltage

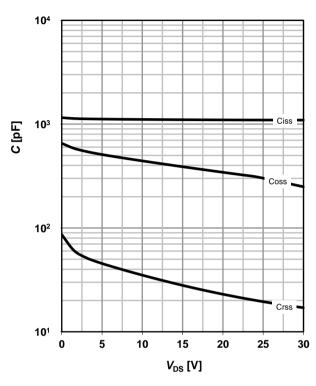
 $V_{GS(th)} = f(T_i); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. Capacitances⁴⁾

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristicis⁴⁾

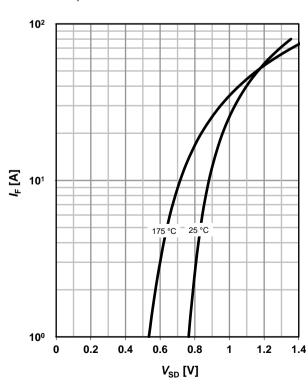
 $IF = f(V_{SD})$

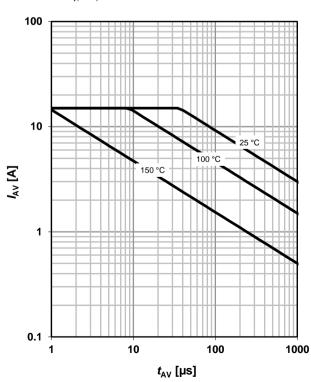
parameter: T_i

12 Avalanche characteristics⁴⁾

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}





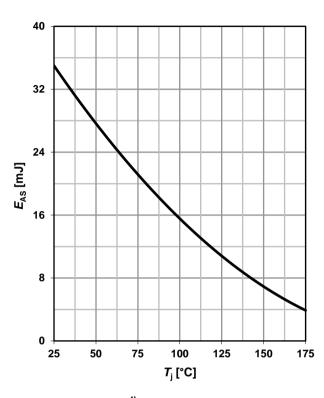


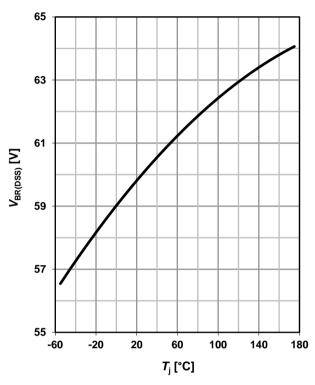
13 Avalanche energy⁴⁾

$$E_{AS} = f(T_i), I_D = 10A$$

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_i); I_D = 1 \text{ mA}$$

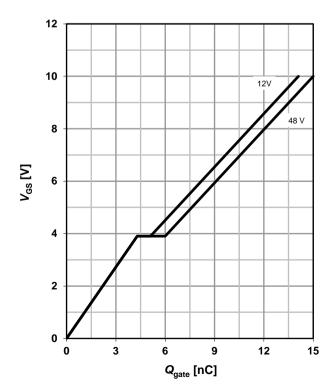




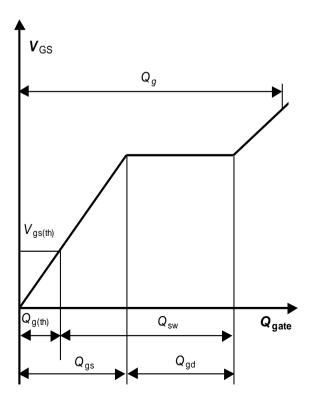
15 Typ. gate charge⁴⁾

 $V_{GS} = f(Q_{gate}); I_D = 20 A pulsed$

parameter: V_{DD}



16 Gate charge waveforms





Published by Infineon Technologies AG 81726 Munich, Germany

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Revision History

Version	Date	Changes
Revision 1.0	15.10.2010	Data Sheet revision 1.0
Revision 1.01	21.03.2024	Package naming updated